

Search Notes



Application/Control No.

10/730,302

Examiner

Mark K. Han

Applicant(s)/Patent under Reexamination

NEER ET AL.

Art Unit

3767

SEARCHED

Class	Subclass	Date	Examiner
604	131 151	3/20/2006	mlh.
	152 154		
	181 187		
	188 207		
	208 209		
	210 211		
	218 228		
	232 234		
	500 155		
128	dig. 1		
	dig. 12		
222	326		
	327		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
as	above	3/20/2006	mlh.
interference search history printout		3/20/2006	mlh.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Inventor name search	6/28/2004	mlh.
EAST text search	3/20/2006	mlh.